# Notice of References Cited Application/Control No. 10/615,878 Applicant(s)/Patent Under Reexamination YUEH, WEN-HSIANG Examiner Tadesse Hailu Art Unit Page 1 of 2

# **U.S. PATENT DOCUMENTS**

*		Document Number . Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-2003/0234776	12-2003	Konishi, Isao	345/204
*	В	US-2005/0020320	01-2005	Lavelle et al.	455/569.2
*	С	US-2003/0125070	07-2003	Wagner et al.	455/550
*	D	US-2004/0155861	08-2004	Jackson III, Robert P.	345/156
*	Ε	US-2003/0137805	07-2003	Wu, Roger	361/686
*	F	US-7,019,737	03-2006	Asai et al.	345/211
*	G	US-6,944,480	09-2005	Tanaka et al.	455/566
*	Н	US-6,877,099	04-2005	Sameshima et al.	713/324
*	1	US-6,781,635	08-2004	Takeda, Genyo	348/552
*	J	US-6,784,855	08-2004	Matthews et al.	345/1.1
*	К	US-6,421,232	07-2002	Sallam, Hussein	361/681
*	۲	US-6,574,488	06-2003	Oba et al.	455/566
*	М	US-2004/0005914	01-2004	Dear, Jean Paul	455/563

## **FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	· Country	Name	Classification
	N					
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# **NON-PATENT DOCUMENTS**

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Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

# Notice of References Cited Application/Control No. 10/615,878 Applicant(s)/Patent Under Reexamination YUEH, WEN-HSIANG Examiner Tadesse Hailu Art Unit Page 2 of 2

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-5,757,354	05-1998	Kawamura, Hiroshi	345/656
*	В	US-6,460,109	10-2002	Kaply et al.	710/316
*	С	US-6,760,010	07-2004	Webb, Geoffrey J. H.	345/168
*	D	US-6,493,734	12-2002	Sachs et al.	715/526
*	Е	US-6,052,120	04-2000	Nahi et al.	715/700
*	F	US-2004/0010599	01-2004	Otobe, Takashi	709/228
*	G	US-2004/0061706	04-2004	Cronin et al.	345/629
	Н	US-			
	1	US			
	J	US-			
	К	US-			
	L	US-			
	M	US-			

# **FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
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### **NON-PATENT DOCUMENTS**

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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

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